

ISO/~~DIS~~**FDIS** 21068-4:2023(E)

~~2023-09~~

ISO/TC 38

Secretariat: BSI

Date: 2024-02-13

Chemical analysis of raw materials and refractory products containing silicon-carbide, silicon-nitride, silicon-oxynitride and sialon

**Part 4:
XRD methods**

Analyse chimique des matières premières et des produits réfractaires contenant du carbure de silicium, du nitrure de silicium, ~~oxynitrure~~ de l'oxynitrure de silicium et ~~sialon~~ du SiAlON

Partie 4: Méthodes de ~~XRD~~DRX

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Introduction

The ISO 21068 series has been developed from the combination of EN 12698-1:2007^[1] and EN 12698-2:2007^[2] and ISO 21068-1:2008^[3], ISO 21068-2:2008^[4] and ISO 21068-3:2008^[5]. The latter has been originally developed from the combination of Japanese standard JIS R 2111:2007^[6] and work items developed within CEN. Because there is a wide variety of laboratory equipment in use, the most commonly used methods are described.

This document is derived from EN 12698-2:2007^[2] describing XRD methods for the determination of mineralogical phases typically apparent in nitride and oxy-nitride bonded silicon carbide refractory products using a Bragg-Brentano diffractometer.

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